## **VOLUME CONTENTS**

VOLUME 33, NUMBER 1		JAN 1993	PAGES 1-114
A. Rangan and G. Sarada	1	Some results on the life distribution prop to shocks and general repair	erties of systems subject
P. K. Kapur, R. B. Garg and V. K. Bhalla	7	Release policies with random software life	e cycle and penalty cost
Yow-mow Chen, T. Fujisawa and H. Ōsawa	13	Availability of the system with general repshut-off rules	air time distributions and
V. M. Cătuneanu, C. Moldovan, Fl. Popentiu, D. N. Boros and D. Popovici	21	Pilots learning time evaluation under co	est constraints
S. K. Johri and V. P. Gupta	27	Preliminary test estimator of average life	in a life test experiment
S. K. Johri and V. P. Gupta	33	Estimation after preliminary test of significant presence of outliers	cance in life testing in the
M. S. Finkelstein	41	A scale model of general repair	
T. Seki and S. Yokoyama	45	Simple and robust estimation of the Wei	bull parameters
G. R. Hofmeister, A. M. Ibrahim and G. A. Shadia	53	On a linear diophantine problem of Frob	enius
D. R. Wingo	57	Maximum likelihood estimation of parameters using interval data	exponential distribution
Gin-Shuh Liang and Mao-Jiun J. Wang	63	Evaluating human reliability using fuzzy	relation
G. Xia, P. Zeephongsekul and S. Kumar	81	Optimal software release policy with a leadebugging	arning factor for imperfect
B. S. Dhillon and O. C. Anude	87	Common-cause failure analysis of a n system with arbitrarily distributed repair	
	105	Book Reviews Pressure Sensors	
		Statistical Methods	
		Handbook of Polymer Coatings for Elec	tronics
		Electromagnetic Compatibility	
		Data Communications Testing and Trou	bleshooting
		Computers and Microprocessors Compo	nents and Systems
	113	Calendar of International Conferences, Meetings of Interest	Symposia, Lectures and
VOLUME 33, NUMBER 2		JAN 1993	PAGES 115-284
M. S. Finkelstein	115	Some notes on wear-dependent systems	S
L. R. Goel, Rakesh Gupta and V. S. Rana	119	Reliability analysis of a satellite-based network system	computer communication
Rakesh Gupta and Alka Chaudhary	127	A multi-component standby system so truncated normal failure time distribution	

Virendra Singh Rana	133	Stochastic analysis of an information computer network system
Dilip Roy	141	Characterizations through failure rate and mean residual life transforms
R. K. Nahar, N. M. Devashrayee, O. P. Wadhawan and P. D. Vyas	143	The filling of via-holes by a sputtered AISi alloy and the development of a two-level metallisation structure
M. Xie and M. Zhao	149	On some reliability growth models with simple graphical interpretations
G. R. Hofmeister, A. M. Ibrahim and G. A. Shadia	169	On the packing sums of pairs
C. Rami Reddy	175	Optimisation of ${\it K}$ -out-of- ${\it N}$ systems subject to common-cause failures with repair provision
Min Huang and M. A. Styblinski	185	An iterative approach to VLSI circuit lifetime estimation
R. P. Anjard Sr	195	Bibliography of current publications concerned with statistical techniques (including SPC) in general, specific statistical techniques, applicable software; also: cost of quality, deming, related history, Japanese approaches, procurement, QFD, training, TQM and selected general quality articles
R. P. Anjard Sr	211	The basis of DBMS (data base management systems) for quality professionals
H. H. Liu, W. T. Yang and C. C. Liu	221	An improved minimizing algorithm for the sum of disjoint products with the inversion of a single variable
R. M. Jacobs	239	Baldrige—a quality philosophy
Mingjian Zuo	243	Reliability and component importance of a consecutive- $k$ -out-of- $n$ system
M. Dohnal, M. Kvapilik, J. Dohnalova and J. Vykydal	259	A chaos based revitalization of large reliability knowledge bases
Anil K. Sarje	267	Technical Notes On the reliability computation of a k-out-of-n system
S. K. Johri and B. L. Agarwal	271	Admissibility of a conditionally specified test procedure for time censored life data
Virendra Singh Rana	273	Reliability analysis of a fault tolerant computer system
	279	Book Reviews Reliability Analysis and Prediction
		Reliability Centred Maintenance—Management and Engineering Methods
	283	Calendar of International Conferences, Symposia, Lectures and Meetings of Interest
VOLUME 33, NUMBER 3		FEB 1993 PAGES 285-450
G. V. Krishna Reddy, R. Nadarajan and P. R. Kandasamy	285	Queues with two units connected in series with a multiserver general bulk service in unit II

P. P. Gupta and M. K. Sharma

L. R. Goel and S. Z. Mumtaz

L. R. Goel, Rakesh Gupta and V. S. Rana

B. Ksir and S. Gandjo	307	Analysis of a repairable two-unit parallel redundant system with failure and repair times arbitrarily distributed
B. Ksir and M. Boushaba	313	Reliability bounds and direct computation of the reliability of a consecutive k-out-of-n: F system with Markov dependence
R. K. Tuteja and Gulshan Taneja	319	Profit analysis of a one-server one-unit system with partial failure subject to random inspection
L. Råde	323	Reliability equivalence
N. Singh	327	An application of time-dependent ARMA models to reliability-decay processes
Who Kee Chung	331	Reliability analysis of a $k$ -out-of- $N:G$ redundant system in the presence of chance with multiple critical errors
G. S. Mokaddis, S. W. Labib and Kh. M. El-Said	335	Cost-benefit analysis of a two-unit warm standby reliability system with two types of repair facilities
G. S. Mokaddis, S. S. Elias, S. A. Metwally and E. A. Soliman	349	A renewable single-server queueing system with priorities
G. S. Mokaddis and C. H. Matta	359	Optimal control output policies of a reservoir subject to Wiener inputs
Y. S. Sherif and Do Le Minh	373	Improving the statistical efficiency of computer simulation experiments
Y. S. Sherif	385	The analysis of simulation experiments
J. Biernat	395	A unified algorithm of reliability estimation of $k$ -out-of- $n$ systems implied by the structure function
A. Noore	403	The effect on yield and chip-area utilization of large fault-tolerant processor clusters
B. S. Dhillon and O. C. Anude	413	Robot safety and reliability: a review
B. S. Dhillon and N. Yang	431	Human error analysis of a standby redundant system with arbitrarily distributed repair times
V. S. Kouikoglou	445	Technical Note A note on the design of k-out-of-n systems
	447	Book Review Handbook of Measurement Science
	449	Publications, Notices and Calls for Papers, etc.
VOLUME 33, NUMBER 4		MAR 1993 PAGES 451-622
Yisong Dai	451	An application of an artificial neural network to reliability screen classification from noise measurement
Banarasi, S. N. S. Kushwaha and K. S. Kushwaha	455	A class of ratio, product and difference (R.P.D.) estimators in systematic sampling
M. C. Rander, A. Kumar and R. K. Tuteja	459	Reliability analysis of a complex redundant system
K. K. Sharma and R. S. Rana	463	Bayesian sequential reliability test plans for a series system
K. K. Sharma and R. S. Rana	467	Robustness of sequential Weibull life-test plans
S. K. Johri and V. P. Gupta	471	Preliminary test interval estimation in life testing in the presence o outliers
T. S. Uma Maheswari, A. Rekha and	477	Reliability comparison of an n cascade system with the addition

M. A. Aziz, M. A. Sobhan and M. A. Samad	481	Enumeration of pathsets of reliability graphs by repeated indexing
A. D. Jerome Stanley	489	On geometric processes and repair replacement problems
S. K. Singh and G. C. Sharma	493	Markovian analysis of the $M^{\rm X}/{\cal E}_{\rm k}/1$ machine repair problem with spares
A. Y. Yehia and M. Gharib	497	Characterizations of the Markov-Bernoulli geometric distribution
S. E. Moafi B., L. R. Goel and R. Gupta	501	Comparison of two stochastic alternative phase models
K. Shankar Bhat and M. Gururajan	509	A two-unit cold standby system with imperfect repair and excessive availability period
G. V. Krishna Reddy, R. Nadarajan and P. R. Kandasamy	513	Tandem queue with three multiserver units and bulk service in unit III
R. Singh, S. K. Upadhyay and U. Singh	521	Bayesian estimators of exponential parameters utilizing a guessed estimate of location
P. K. Bansal, K. Singh and R. C. Joshi	529	Reliability and performance analysis of a modular multistage interconnection network
J. H. Huang, Y. Y. Qian, Y. H. Jiang and Q. L. Wang	535	A dislocation model of shear fatigue damage and life prediction of SMT solder joints under thermal cycles
A. Lešanovský	543	Minimal size of the system with two dual modes of failure having prescribed reliability
G. L. Schnable, K. M. Schlesier, G. A. Swartz and C. P. Wu	565	Impact of anomalous short-channel MOS transistors on VLSI circuit reliability
Gin-Shuh Liang and Mao-Jiun J. Wang	583	Fuzzy fault-tree analysis using failure possibility
H. H. Liu, W. T. Yang and C. C. Liu	599	An improved minimizing algorithm for the summation of disjoint products by Shannon's expansion
H. Reiche	615	Society of Reliability Engineers Bulletin
	617	Book Reviews Reliability, Availability, and Safety Assessment. Volume 1: Methods and Techniques. Volume 2: Assessment, Hardware, Software and Human Factors.
		Reliability Engineering Handbook: Volume 1
	621	Publications, Notices, Calls for Papers, etc.
VOLUME 33, NUMBER 5		APR 1993 PAGES 623-770
S. A. Salem and F. A. El-Glad	623	Bayesian prediction for the range based on a two-parameter exponential distribution with a random sample size
C. Yang	633	Linear dependency check in built-in test
Shibin Song and Yonglu Deng	637	Reliability analysis of a three-unit system in a changing environment
R. P. Anjard Sr	641	A survey of program management software (for PC compatibles) for quality professionals
T. Brożek, B. Pešić, A. Jakubowski and N. Stojadinović	649	Breakdown properties of thin oxides in irradiated MOS capacitors
A. Wild	659	Modern trends in ASIC: mixing technologies
M. S. Finkelstein	663	
K. K. Sharma and Hare Krishna	667	Tolerance limits for system reliability

VIII

A. A. Abdel-Ghaly and A. F. Attia	671	On a new density function
M. O. Abou-El-Ata, R. O. Al-Seedy and K. A. M. Kotb	681	A transient solution of the state-dependent queue: $M/M/1/N$ with balking and reflecting barrier
T. I. Sultan	689	Analysis of quality parameters in the electronic industry to determine the optimum quality level
C. D. Lai	697	Bounds on reliability of a k-out-of-n system
M. A. W. Mohamoud, M. M. Mohie El-Din and M. E. Moshref	705	Reliability study of a two-unit cold standby redundant system with repair of two phases
A. S. Papadopoulos	719	Hierarchical confidence bounds for the exponential failure model
A. M. Abouammoh, A. N. Ahmed and A. M. Barry	729	Shock models and testing for the renewal mean remaining life classes
M. J. LuValle	741	Experiment design and graphical analysis for checking acceleration models
	765	Book Reviews Reliability Engineering Handbook. Volume 2
		Software Reliability Modelling
		Ceramics in Substitutive and Reconstructive Surgery
		Electronic Ceramics
		Error-free Software Know-how and Know-why of Program Correctness

VOLUME 33, NUMBER 6		MAY 1993 PAGES 771–920
M. N. Gopalan and T. Srinivasa	771	Probabilistic analysis of a two-stage production system subject to inspection at first stage and initial buffer
D. M. Petković and N. D. Stojadinović	785	Reliability of polysilicon thin film resistors with irreversible resistance transition
R. Gupta and A. Chaudhary	793	Analysis of a standby system with Rayleigh down time and gamma failure time distributions
K. K. Bansal and R. L. Garg	797	Queue dependent probabilistic additional space heterogeneous queueing problem
K. K. Aggarwal and Y. Singh	803	Determination of software release instant using a nonhomogeneous error detection rate model
K. K. Sharma and R. K. Bhutani	809	Bayesian analysis of system availability
E. S. Abuelyaman	813	On the reliability of links in a ring network
Y. S. Sherif and R. G. Dear	827	Extensions to the Sherif-Dear Simple (SDS) theorem in number theory
A. Y. Yehia and A. N. Ahmed	833	Two characterizations of geometric distributions
T. V. Torchinskaya	845	Kinetics of red AlGaAs light-emitting diodes degradation
A. F. Attia	859	On estimation for mixtures of two Rayleigh distribution with censoring
M. Hershcovitz and I. E. Klein	869	Dynamics of spin coating on very rough surfaces
L. Råde	881	Reliability survival equivalence
J. P. Pierrel, D. May and L. Bourdin	895	FACE: a failure analysis and characterization environment for E-beam testing

P. K. Bhatia, H. C. Taneja and R. K. Tuteja	905	Technical Notes Inaccuracy and the best 1:1 code
S. K. Singh, U. Singh and S. K. Upadhyay	909	Bayes interval for the Weibull parameters utilizing guessed escimates
	913	Publications, Notices, Calls for Papers, etc.
	917	Calendar of International Conferences, Symposia, Lectures and Meetings of Interest
VOLUME 33, NUMBER 7		MAY 1993 PAGES 921-1068
Manju Agarwal and Meenakshi Mahajan	921	Performance-related reliability measures for a repairable two-unit gracefully degrading system
T. S. Uma Maheswari, A. Rekha, E. Anjan Rao and A. C. N. Raghava Char	929	Reliability of a cascade system with normal stress and exponential strength
Tan Min	937	The analysis of the states of buffer in a CIMS production line
M. O. Abou-El-Ata and A. I. Shawky	941	The truncated service time Erlangian overflow queues with balking
S. K. Ghosh and Brijendra Singh	947	Enumeration of minimal cutsets from matrix representation of directed/undirected networks
L. V. Utkin	951	The paradox of monotony of systems by fuzzy probability
D. M. Brkić	957	$\ensuremath{\textit{B}}\xspace$ -test of goodness of fit of an empirical distribution to a supposedly theoretical one
A. M. Rushdi and A. A. Abdulghani	965	A comparison between reliability analyses based primarily on dis- jointness or statistical independence: the case of the generalized Indra network
A. M. Rushdi and K. A. Al-Hindi	979	A table for the lower boundary of the region of useful redundancy for $k$ -out-of- $n$ systems
M. Sanada	993	New application of laser beam to failure analysis of LSI with multi-metal layers
S. P. Sim	1011	The reliability of laser diodes and laser transmitter modules
J. Suñé, M. Nafría and X. Aymerich	1031	Reversible dielectric breakdown of thin gate oxides in MOS devices
D. Badenius	1041	Technical Notes Note on integrity versus reliability
J. Y. Wong	1045	A note on solving a system reliability problem
S. P. Mukherjee and D. Roy	1053	A versatile failure time distribution
K. M. Garg, M. Jain and G. C. Sharma	1057	$G/G^{\nu}/m$ queueing system with discouragement via diffusion approximation
P. P. Gupta and Shashi Sharma	1061	Reliability analysis of a three-state multi-component warm standby redundant complex system with waiting for repair
	1065	Book Reviews Quality Through Engineering Design Microelectronics Manufacturing Diagnostics Handbook
VOLUME 33, NUMBER 8		JUN 1993 PAGES 1069–1218
W. Li and J. Cao	1069	Limiting distributions of the residual lifetimes of several repairable systems

R. Gupta, A. Chaudhary and R. Goel	1073	Profit analysis of a two-unit priority standby system subject to
n. Gupta, A. Chaudhary and h. Goel	10/3	degradation and random shocks
K. K. Sharma and H. Krishna	1081	Reliability bounds for some static system models using lifetime data on their components
P. K. Bhatia and H. C. Tenaja	1085	Coding theorems on a generalized "useful" inaccuracy
K. K. Aggarwal and S. Guha	1089	Reliability allocation in a general system with non-identical components—a practical approach
K. C. Kurien, G. S. Sekhon and O. P. Chawla	1095	Reliability and ageing of repairable systems
D. Kumar, J. Singh and P. C. Pandey	1101	Operational behaviour and profit function for a bleaching and screening system in the paper industry
L. R. Goel and S. Z. Mumtaz	1107	A homogeneous Markov model for phased-mission reliability characteristics
N. K. Singh and S. K. Bhattacharya	1113	Bayesian analysis of the mixture of exponential failure distributions
K. K. Das and D. Acharya	1119	A model for optimal repair-effort decision for standby redundant systems with common-cause failures and its application to pulverizer systems
A. Y. Yehia	1127	On a characterization by residual moment
M. M. Alidrisi	1133	Availability of pavements with random crack times and regular inspection
B. Vanhecke, L. De Schepper, W. De Ceuninck, V. D'Haeger, M. D'Olieslaegers, E. Beyne, J. Roggen and L. Stals	1141	Electromigration: investigation of heterogeneous systems
MT. Lai and J. Yuan	1159	Cost-optimal periodical replacement policy for a system subjected to shock damage
C. M. Krishna	1169	The impact of workload on the reliability of real-time processor triads
S. K. Ashour and M. A. M. H. El-Wakeel	1179	Bayesian prediction of the /th order statistic with Burr distribution and a random sample size
E. Castaño and J. Maiz	1189	Physical analysis of electromigration damage under non-d.c. conditions
O. A. Shalaby and El-Yousef	1199	Bayesian analysis of the parameters of a doubly truncated Weibull distribution
J. Y. Wong	1213	Technical Note A note on solving a system reliability problem involving nonlinear constraints
VOLUME 33, NUMBER 9		JUL 1993 PAGES 1219–1438
R. K. Agnihotri, V. Kumar and M. A. Ansari	1219	Stochastic analysis of a system operating in a multiple environment
K. K. Sharma and R. S. Rana	1223	Robust character of exponential SPRT
O. N. Martynenko	1227	Optimization of restoration cost for complex technical systems at centralized structure of repair
M. A. Aziz, M. A. Sobhan and M. A. Samad	1233	Empirical formulas and global reliability evaluation of reliability graphs
Y. Deng and S. Song	1237	Reliability analysis of a multicomponent system in a multistate Markovian environment

D. Rath and K. P. Soman	1241	A simple method for generating $K$ -trees of a network
P. K. Kapur, S. Bhushan and S. Younes	1245	An exponential SRGM with a bound on the number of failures
D. R. Wingo	1251	Maximum likelihood estimation of Burr XII distribution parameters under Type II censoring
L. R. Jaisingh and D. T. Calland	1259	Bayesian estimation under Poisson testing using the LINEX loss function
S. K. Singh and R. B. Singh	1267	Cost analysis of a man-machine system operating under changing operator conditions
Tan Min	1275	The reliability model on a two stage CIMS production line
N. R. Chaganty and R. Mukkamala	1281	Order statistics based modeling of gracefully degrading computing systems
KH. Wang	1293	Cost analysis of the $M/M/R$ machine-repair problem with mixed standby spares
M. M. Atiqullah and S. S. Rao	1303	Reliability optimization of communication networks using simulated annealing
B. S. Dhillon and O. C. Anude	1321	Common-cause failure analysis of a parallel system with warm standby
B. S. Dhillon	1343	Reliability and availability analysis of a system with warm standby and common cause failures
S. S. Elias, N. Mokhles and S. A. N. Ibrahim	1351	A new technique in a cutset evaluation
L. V. Utkin	1357	Uncertainty importance of system components by fuzzy and interval probability
S. Cristoloveanu, H. Haddara and N. Revil	1365	Defect localization induced by hot carrier injection in short-channel MOSFETs: concept, modeling and characterization
I. S. Qamber	1387	Flow graph development method
K. Bock and HL. Hartnagel	1397	ESD-degradation mechanisms of GaAs microwave devices and device protection
J. Y. Wong	1411	Technical Notes A note on reliability allocation under a preventative maintenance schedule
M. Jain	1415	Diffusion equation for $GI^{\times}/G/r$ machine interference problem with spare machines
	1419	World Abstracts on Microelectronics and Reliability

VOLUME 33, NUMBER 10		AUG 1993 PAGES 1439–1634
G. W. A. Dummer	1439	Editorial
V. Benda and P. Špůr	1441	A simple method of in-process checking of the large area GTO homogeneity
W. Li and DH. Shi	1447	Reliability analysis of a two-unit parallel system with "preemptive priority" rule
K. P. Soman and K. B. Misra	1455	On Bayesian estimation of system reliability
L. R. Goel, R. Gupta and V. S. Rana	1461	Analysis of a multiunit solar energy system model

R. K. Agnihotri, V. Kumar and M. A. Ansari	1467	Stochastic analysis of a redundant system with two types of failure
H. Reiche and A. P. Harris	1473	A simple spares model using Weibull theorems
N. Mokhles and A. Abo El-Fotouh	1477	Stochastic behaviour of a standby redundant repairable complex system under various modes of failure
B. S. Dhillon and O. C. Anude	1499	Common-cause failure analysis of a redundant system with non-repairable units
B. S. Dhillon and N. Yang	1511	Availability of a man-machine system with critical and non-critical human error
S. K. Ashour and M. A. M. H. El-Wekeel	1523	Bayesian prediction of the life times of the unused items for the Burr distributions with a random sample size
A. A. Gagin	1533	Methods and models for computing survivability and fault-tolerance of a network
J. Y. Wong	1553	A note on determining component reliability and redundancy
J. Y. Wong	1561	Estimating the three Weibull parameters by maximizing the logarithm of the likelihood function directly
O. Chryssaphinou, S. Papastavridis and T. Tsapelas	1567	A general repairable system with ${\cal N}$ failure modes and ${\it k}$ standby units
M. Sfakianakis	1573	Optimal arrangement of components in a consecutive $k$ -out-of- $r$ -from $n$ : F system
P. Cappelletti, P. Ghezzi, F. Pio and C. Riva	1579	Wafer level tunnel oxide reliability evaluation by means of the Exponentially Ramped Current Stress method
A. Lešanovský	1597	Systems with two dual failure modes—a survey
	1627	Society of Reliability Engineering Bulletin
	1629	Book Reviews Maintenance Minimization for Competitive Advantage Reliability and Life Testing Handbook. Volume 1 Contamination Control and Cleanrooms
	1622	Bublications Nations Calle for Banana ata

VOLUME 33, NUMBER 11/12 SEP 1993 PAGES 1635–1956

## RELIABILITY PHYSICS OF ADVANCED ELECTRON DEVICES

N. D. Stojadinović	1635	Editorial
Γ. Brożek and A. Jakubowski	1637	Dielectric integrity of thin thermal oxides on silicon
F. Pio, L. Ravazzi and C. Riva	1657	Influence of series resistance in oxide parameter extraction data from accelerated tests
RP. Vollertsen	1665	Statistical modelling of time dependent oxide breakdown distributions
P. O'Sullivan and A. Mathewson	1679	Implications of a localised defect model for wafer level reliability measurements of thin dielectrics
E. Takeda	1687	Hot-carrier effects in scaled MOS devices
P. Fang, R. Rakkhit and J. T. Yue	1713	An investigation of hot carrier effects in submicron CMOS integrated circuits

W. Weber and M. Brox	1729	Dynamic effects in hot-carrier degradation relevant for CMOS operation
H. Wang and M. Davis	1737	Transient hot-electron effect and its impact on circuit reliability
J. Oualid, S. Burgniard, E. Ciantar and R. Jérisian	1759	Hot-carrier effects on leakage currents in MOSFETs—modelling and experiment
G. L. Baldini, I. De Munari, A. Scorzoni and F. Fantini	1779	Electromigration in thin-films for microelectronics
M. J. Dion	1807	On the status of wafer-level metal integrity testing
B. K. Jones and Y. Z. Xu	1829	Characterisation of electromigration damage by multiple electrical measurements
G. L. Baldini, A. Scorzoni and F. Tamarri	1841	Resistance decay after electromigration as the effect of mechanical stress relaxation
A. B. Joshi and DL. Kwong	1845	Reliability issues in submicron MOSFETs with oxynitride gate dielectrics
C. Papadas, G. Ghibaudo, C. Monserié and G. Pananakakis	1867	Reliability issues of silicon-dioxide structures—application to FLOTOX EEPROM cells
N. Revil, S. Cristoloveanu and P. Mortini	1909	A comparison of MOSFETs aging under d.c., a.c. and alternating stress conditions
C. Papadas, P. Mortini, C. Monserié, G. Ghibaudo and G. Pananakakis	1921	Reliability issues of offset drain transistors after different modes of static electrical stress
M. Shell-De Guzman, M. Mahaney and R. Strode	1935	The in-process bond shear test: its relationship to ball bond reliability and its application to the reduction of wirebond process variation
M. R. Rodgers, M. A. Wendman and F. D. Yashar	1947	Application of the atomic force microscope to integrated circuit failure analysis
VOLUME 33, NUMBER 13		OCT 1993 PAGES 1957–2078
A. Srivastava	1957	Digital characteristics of a CMOS ternary inverter at the liquid nitrogen temperature
A. M. Rushdi and A. O. Al-Thubaity	1963	Efficient computation of the sensitivity of $k$ -out-of- $n$ system reliability
AZ. H. El-Banna and E. A. Youness	1981	On some basic notions of stochastic multiobjective programming problems with random parameters in the constraints
Fan Chin Meng	1987	On comparison of MTBF between four redundant systems
V. N. Bhat	1991	Renewal approximations of the doubly stochastic Poisson processes
V. N. Bhat	1997	Approximation for the variance of the waiting time in a GI/G/1 queue
A. P. Harris	2003	Useful and available RAM data banks
M. M. A. Ananda and A. K. Singh	2013	Estimation of a composite hazard rate model
L. V. Utkin	2021	Uncertainty importance of multistate system components
H. Arsham	2031	An improved lower bound for the right tail of the reliability function under a type-two censoring plan
M. Pandey and V. P. Singh	2039	Bayes shrinkage estimation of reliability and the parameters of a finite range failure time model

Md. B. Uddin, M. Pandey, J. Ferdous and M. R. Bhuiyan	2043	Estimation of reliability in a multicomponent stress-strength model
S. Pidin	2047	A method of threshold voltage and current gain factor estimation for CMOS IC input transistors
Gu Hai-Yan and He You-Hua	2053	Technical Note The closeness for {NBU} and {NWU}
	2055	World Abstracts on Microelectronics and Reliability
	2077	Publications, Notices, Calls for Papers, etc.
VOLUME 33, NUMBER 14		NOV 1993 PAGES 2079–2178
A. Wild and H. Fischer	2079	Modeling metastable states in ASIC
D. R. Sparks, K. T. Hankins and A. J. Levitan	2087	Hot-carrier effects in polysilicon emitter vertical PNP and NPN transistors
A. Aissani	2093	Unreliable queuing with repeated orders
M. Decréton, A. Benemann, R. Sharp, S. Coenen, D. Van Beckhoven, J. Podgorski and L. Pater	2107	Influence of the testing environment in bipolar transistors radiation resistance results: a benchmark exercise
G. S. Mokaddis, S. W. Labib and Kh. M. El-Said	2119	Availability analysis of a two dissimilar-unit deteriorating standby system with inspection
M. C. Bhattacharjee	2143	Aging renewal process characterizations of exponential distributions
AZ. H. El-Banna and E. A. Youness	2149	On stability of stochastic multiobjective programming problems with random coefficients in the objective functions
R. K. Nahar	2153	Technical Notes The yield models and defect density monitors for integrated circuit diagnosis
S. Patra and R. B. Misra	2161	Reliability evaluation of flow networks considering multistate modelling of network elements
L. R. Goel and V. K. Tyagi	2165	A two unit series system with correlated failures and repairs
	2171	Calendar of International Conferences, Symposia, Lectures and Meetings of Interest
	2175	Publications, Notices, Calls for Papers, etc.
VOLUME 33, NUMBER 15		DEC 1993 PAGES 2179–2300
M. Huang and M. A. Styblinski	2179	GOSSIP_DR: a generic software system for IC reliability optimization
O. A. Shalaby	2189	The Bayes risk for the parameters of doubly truncated Weibull distribution
W. K. Chung	2193	Availability and frequency of warm standby systems in the presence of chance with multiple critical errors
L. V. Utkin	2197	A new heuristic method redundancy optimization in a consecutive- $k$ -out-of- $n$ : F system by fuzzy probability
Y. Dai	2207	A dynamic noise measurement technique used to estimate activation energies for failure mechanisms of a transistor

J. Y. Wong	2217	Simultaneously estimating the three Weibull parameters from progressively censored samples
J. Y. Wong	2225	Simultaneously estimating the three parameters of the generalized gamma distribution
J. Y. Wong	2233	Simultaneously estimating with ease the three parameters of the generalized gamma distribution
J. Y. Wong	2243	Readily obtaining the maximum likelihood estimates of the three parameters of the generalized gamma distribution of Stacy and Mihram
KY. Cai, CY. Wen and ML. Zhang	2253	Fuzzy states as a basis for a theory of fuzzy reliability
KY. Cai, CY. Wen and ML. Zhang	2265	A novel approach to software reliability modeling
B. Singh	2269	A procedure for generating sums of disjoint products
U. Singh, S. K. Upadhyay and A. N. Rai	2273	Technical Notes Estimation of average life for negative exponential distribution
R. Gupta and A. Chaudhary	2277	A two-unit system subject to a partial-failure mode and gamma repair-time distribution
L. R. Goel, R. Gupta and P. K. Tyagi	2281	Cost benefit analysis of a complex system with correlated failures and repairs
D. Roy	2285	Estimation of failure probability under a bivariate normal stress-strength distribution
R. L. Garg and P. Singh	2289	Queue-dependent servers queueing system
	2297	Book Reviews Stochastic Models of Reliability Theory (Modèles Stochastiques de la Théorie de Fiabilité)
		Ultraclean Technology Handbook. Volume 1: Ultrapure Water
	٧	Title Section, Volume Contents and Author Index, Volume 33, 1993

